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Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.333GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	1023-BBGA, FCBGA
Supplier Device Package	1023-FCPBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8572eclvjaule

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

NOTE

From a system standpoint, if any of the I/O power supplies ramp prior to the VDD core supply, the I/Os associated with that I/O supply may drive a logic one or zero during power-on reset, and extra current may be drawn by the device.

3 Power Characteristics

The estimated typical power dissipation for the core complex bus (CCB) versus the core frequency for this family of PowerQUICC III devices with out the L in its part ordering is shown in Table 4.

CCB Frequency	Core Frequency	Typical-65 ²	Typical-105 ³	Maximum ⁴	Unit
533	1067	12.3	17.8	18.5	W
533	1200	12.3	17.8	18.5	W
533	1333	16.3	22.8	24.5	W
600	1500	17.3	23.9	25.9	W

Table 4	MPC8572F	Power	Dissir	nation ¹
		I OWEI	Diagih	Jation

Notes:

¹ This reflects the MPC8572E power dissipation excluding the power dissipation from B/G/L/O/T/XV_{DD} rails.

 $^2~$ Typical-65 is based on V_DD = 1.1 V, T_j = 65 °C, running Dhrystone.

³ Typical-105 is based on V_{DD} = 1.1 V, T_i = 105 °C, running Dhrystone.

⁴ Maximum is based on V_{DD} = 1.1 V, T_j = 105 °C, running a smoke test.

The estimated typical power dissipation for the core complex bus (CCB) versus the core frequency for this family of PowerQUICC III devices with the L in its port ordering is shown in Table 5.

CCB Frequency	Core Frequency	Typical-65 ²	Typical-105 ³	Maximum ⁴	Unit
533	1067	12	15	15.8	W
533	1200	12	15.5	16.3	W
533	1333	12	15.9	16.9	W
600	1500	13	18.7	20.0	W

Table 5. MPC8572EL Power Dissipation ¹

Notes:

¹ This reflects the MPC8572E power dissipation excluding the power dissipation from B/G/L/O/T/XV_{DD} rails.

² Typical-65 is based on V_{DD} = 1.1 V, T_j = 65 °C, running Dhrystone.

³ Typical-105 is based on V_{DD} = 1.1 V, T_i = 105 °C, running Dhrystone.

 4 Maximum is based on V_{DD} = 1.1 V, T_i = 105 °C, running a smoke test.



4 Input Clocks

4.1 System Clock Timing

Table 6 provides the system clock (SYSCLK) AC timing specifications for the MPC8572E.

Table 6. SYSCLK AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3V ± 5%.

Parameter/Condition	Symbol	Min	Typical	Мах	Unit	Notes
SYSCLK frequency	f _{SYSCLK}	33	—	133	MHz	1
SYSCLK cycle time	t _{SYSCLK}	7.5	—	30.3	ns	—
SYSCLK rise and fall time	t _{KH} , t _{KL}	0.6	1.0	1.2	ns	2
SYSCLK duty cycle	t _{KHK} /tsysclk	40	—	60	%	3
SYSCLK jitter	—	—	—	+/- 150	ps	4, 5, 6

Notes:

1. **Caution:** The CCB clock to SYSCLK ratio and e500 core to CCB clock ratio settings must be chosen such that the resulting SYSCLK frequency, e500 (core) frequency, and CCB clock frequency do not exceed their respective maximum or minimum operating frequencies. Refer to Section 19.2, "CCB/SYSCLK PLL Ratio," and Section 19.3, "e500 Core PLL Ratio," for ratio settings.

- 2. Rise and fall times for SYSCLK are measured at 0.6 V and 2.7 V.
- 3. Timing is guaranteed by design and characterization.
- 4. This represents the total input jitter—short term and long term—and is guaranteed by design.
- 5. The SYSCLK driver's closed loop jitter bandwidth should be <500 kHz at -20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track SYSCLK drivers with the specified jitter.
- 6. For spread spectrum clocking, guidelines are +0% to -1% down spread at a modulation rate between 20 kHz and 60 kHz on SYSCLK.

4.2 Real Time Clock Timing

The RTC input is sampled by the platform clock (CCB clock). The output of the sampling latch is then used as an input to the counters of the PIC and the TimeBase unit of the e500. There is no jitter specification. The minimum pulse width of the RTC signal should be greater than 2x the period of the CCB clock. That is, minimum clock high time is $2 \times t_{CCB}$, and minimum clock low time is $2 \times t_{CCB}$. There is no minimum RTC frequency; RTC may be grounded if not needed.



4.3 eTSEC Gigabit Reference Clock Timing

Table 7 provides the eTSEC gigabit reference clocks (EC_GTX_CLK125) AC timing specifications for the MPC8572E.

Table 7. EC_GTX_CLK125 AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 3.3V ± 5% or 2.5V ± 5%

Parameter/Condition	Symbol	Min	Typical	Мах	Unit	Notes
EC_GTX_CLK125 frequency	f _{G125}	—	125	—	MHz	—
EC_GTX_CLK125 cycle time	t _{G125}	—	8	—	ns	_
EC_GTX_CLK125 rise and fall time L/TV_DD=2.5V L/TV_DD=3.3V	t _{G125R} , t _{G125F}	_	_	0.75 1.0	ns	1
EC_GTX_CLK125 duty cycle GMII, TBI 1000Base-T for RGMII, RTBI	t _{G125H} /t _{G125}	45 47	_	55 53	%	2, 3

Notes:

1. Rise and fall times for EC_GTX_CLK125 are measured from 0.5V and 2.0V for L/TV_{DD}=2.5V, and from 0.6V and 2.7V for L/TV_{DD}=3.3V.

- 2. Timing is guaranteed by design and characterization.
- 3. EC_GTX_CLK125 is used to generate the GTX clock for the eTSEC transmitter with 2% degradation. EC_GTX_CLK125 duty cycle can be loosened from 47/53% as long as the PHY device can tolerate the duty cycle generated by the TSEC*n*_GTX_CLK. See Section 8.2.6, "RGMII and RTBI AC Timing Specifications," for duty cycle for 10Base-T and 100Base-T reference clock.

4.4 DDR Clock Timing

Table 8 provides the DDR clock (DDRCLK) AC timing specifications for the MPC8572E.

Table 8. DDRCLK AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3V ± 5%.

Parameter/Condition	Symbol	Min	Typical	Мах	Unit	Notes
DDRCLK frequency	f _{DDRCLK}	66	—	100	MHz	1
DDRCLK cycle time	t _{DDRCLK}	10.0	—	15.15	ns	_
DDRCLK rise and fall time	t _{KH} , t _{KL}	0.6	1.0	1.2	ns	2
DDRCLK duty cycle	t _{KHK} /t _{DDRCLK}	40	—	60	%	3



PLL config input setup time with stable SYSCLK before HRESET negation	100	_	μs	
Input setup time for POR configs (other than PLL config) with respect to negation of HRESET	4		SYSCLKs	1
Input hold time for all POR configs (including PLL config) with respect to negation of HRESET	2	_	SYSCLKs	1
Maximum valid-to-high impedance time for actively driven POR configs with respect to negation of HRESET	—	5	SYSCLKs	1

Table 9. RESET Initialization Timing Specifications (continued)

Notes:

2. Reset assertion timing requirements for DDR3 DRAMs may differ.

Table 10 provides the PLL lock times.

Table	10.	PLL	Lock	Times
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Parameter/Condition	Symbol	Min	Typical	Max
PLL lock times	_	100	μs	—
Local bus PLL	_	50	μs	_

6 DDR2 and DDR3 SDRAM Controller

This section describes the DC and AC electrical specifications for the DDR2 and DDR3 SDRAM controller interface of the MPC8572E. Note that the required $GV_{DD}(typ)$ voltage is 1.8Vor 1.5 V when interfacing to DDR2 or DDR3 SDRAM, respectively.

6.1 DDR2 and DDR3 SDRAM Interface DC Electrical Characteristics

Table 11 provides the recommended operating conditions for the DDR SDRAM controller of the MPC8572E when interfacing to DDR2 SDRAM.

Parameter/Condition	Symbol	Min	Мах	Unit	Notes
I/O supply voltage	GV _{DD}	1.71	1.89	V	1
I/O reference voltage	MV _{REF} n	$0.49 imes GV_{DD}$	$0.51 imes GV_{DD}$	V	2
I/O termination voltage	V _{TT}	MV _{REF} <i>n</i> – 0.04	$MV_{REF}n + 0.04$	V	3
Input high voltage	V _{IH}	$MV_{REF}n + 0.125$	GV _{DD} + 0.3	V	_
Input low voltage	V _{IL}	-0.3	MV _{REF} n – 0.125	V	_
Output leakage current	I _{OZ}	-50	50	μA	4
Output high current (V _{OUT} = 1.420 V)	I _{OH}	-13.4	_	mA	—

DDDO ODDAM Late	uface DO Electula	al Okawa ataulatiaa	$f_{a,m} = O(1 - (f_{a,m})) = A = O(1)$,
DURZ SURAW INTE	rtace DU Electric	al Unaracteristics	TOT (= V = (TVD) = T A V	

^{1.} SYSCLK is the primary clock input for the MPC8572E.

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Figure 8. FIFO Receive AC Timing Diagram

8.2.2 GMII AC Timing Specifications

This section describes the GMII transmit and receive AC timing specifications.

8.2.2.1 GMII Transmit AC Timing Specifications

Table 27 provides the GMII transmit AC timing specifications.

Table 27. GMII Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition	Symbol ¹	Min	Тур	Max	Unit
GMII data TXD[7:0], TX_ER, TX_EN setup time	t _{GTKHDV}	2.5	—	_	ns
GTX_CLK to GMII data TXD[7:0], TX_ER, TX_EN delay	^t GTKHDX	0.5	—	5.0	ns
GTX_CLK data clock rise time (20%-80%)	t _{GTXR} ²	—	—	1.0	ns
GTX_CLK data clock fall time (80%-20%)	t _{GTXF} 2	—	—	1.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern t_{(first two letters of functional block)(signal)(state) (reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{GTKHDV} symbolizes GMII transmit timing (GT) with respect to the t_{GTX} clock reference (K) going to the high state (H) relative to the time date input signals (D) reaching the valid state (V) to state or setup time. Also, t_{GTKHDX} symbolizes GMII transmit timing (GT) with respect to the high state (H) relative to the time date input signals (D) going invalid (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GTX} represents the GMII(G) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).}

2. Guaranteed by design.



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Figure 14 shows the MII receive AC timing diagram.



Figure 14. MII Receive AC Timing Diagram

8.2.4 TBI AC Timing Specifications

This section describes the TBI transmit and receive AC timing specifications.

8.2.4.1 TBI Transmit AC Timing Specifications

Table 31 provides the TBI transmit AC timing specifications.

Table 31. TBI Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V \pm 5%.

Parameter/Condition	Symbol ¹	Min	Тур	Max	Unit
TCG[9:0] setup time GTX_CLK going high	t _{TTKHDV}	2.0	_	—	ns
TCG[9:0] hold time from GTX_CLK going high	t _{TTKHDX}	1.0	—	—	ns
GTX_CLK rise (20%-80%)	t _{TTXR} ²	_	—	1.0	ns
GTX_CLK fall time (80%–20%)	t _{TTXF} ²	_	_	1.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern of t_{(first two letters of functional block)(signal)(state)} for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TTX} represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

2. Guaranteed by design.



described in Section 21.5, "Connection Recommendations," as long as such termination does not violate the desired POR configuration requirement on these pins, if applicable.

When operating in SGMII mode, the eTSEC EC_GTX_CLK125 clock is not required for this port. Instead, SerDes reference clock is required on SD2_REF_CLK and SD2_REF_CLK pins.

8.3.1 DC Requirements for SGMII SD2_REF_CLK and SD2_REF_CLK

The characteristics and DC requirements of the separate SerDes reference clock are described in Section 15, "High-Speed Serial Interfaces (HSSI)."

8.3.2 AC Requirements for SGMII SD2_REF_CLK and SD2_REF_CLK

Table 37 lists the SGMII SerDes reference clock AC requirements. Note that SD2_REF_CLK and SD2_REF_CLK are not intended to be used with, and should not be clocked by, a spread spectrum clock source.

Symbol	Parameter Description	Min	Typical	Max	Units	Notes
t _{REF}	REFCLK cycle time		10 (8)	_	ns	1
t _{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles		_	100	ps	_
t _{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location	-50		50	ps	

Table 37. SD2_REF_CLK and SD2_REF_CLK AC Requirements

Note:

1.8 ns applies only when 125 MHz SerDes2 reference clock frequency is selected through cfg_srds_sgmii_refclk during POR.



Ethernet Management Interface Electrical Characteristics

Table 45. MII Management AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD}/TV_{DD} of 3.3 V ± 5% or 2.5 V ± 5%.

Parameter/Condition	Symbol ¹	Min	Тур	Мах	Unit	Notes
ECn_MDIO to ECn_MDC setup time	t _{MDDVKH}	5	—	-	ns	_
ECn_MDIO to ECn_MDC hold time	t _{MDDXKH}	0	—	-	ns	_
ECn_MDC rise time	t _{MDCR}	—	—	10	ns	4
ECn_MDC fall time	t _{MDHF}	—	—	10	ns	4

Notes:

1. The symbols used for timing specifications herein follow the pattern of t(first two letters of functional block)(signal)(state)

(reference)(state) for inputs and $t_{(first two letters of functional block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{MDKHDX} symbolizes management data timing (MD) for the time t_{MDC} from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, t_{MDDVKH} symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MDC} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

- 2. This parameter is dependent on the eTSEC system clock speed, which is half of the Platform Frequency (f_{CCB}). The actual ECn_MDC output clock frequency for a specific eTSEC port can be programmed by configuring the MgmtClk bit field of MPC8572E's MIIMCFG register, based on the platform (CCB) clock running for the device. The formula is: Platform Frequency (CCB)/(2*Frequency Divider determined by MIICFG[MgmtClk] encoding selection). For example, if MIICFG[MgmtClk] = 000 and the platform (CCB) is currently running at 533 MHz, $f_{MDC} = 533/(2*4*8) = 533/64 = 8.3$ MHz. That is, for a system running at a particular platform frequency (f_{CCB}), the ECn_MDC output clock frequency can be programmed between maximum $f_{MDC} = f_{CCB}/64$ and minimum $f_{MDC} = f_{CCB}/448$. Refer to MPC8572E reference manual's MIIMCFG register section for more detail.
- 3. The maximum ECn_MDC output clock frequency is defined based on the maximum platform frequency for MPC8572E (600 MHz) divided by 64, while the minimum ECn_MDC output clock frequency is defined based on the minimum platform frequency for MPC8572E (400 MHz) divided by 448, following the formula described in Note 2 above. The typical ECn_MDC output clock frequency of 2.5 MHz is shown for reference purpose per IEEE 802.3 specification.
- 4. Guaranteed by design.
- 5. t_{plb clk} is the platform (CCB) clock.

Figure 28 shows the MII management AC timing diagram.



Figure 28. MII Management Interface Timing Diagram



Local Bus Controller (eLBC)

Figure 30 through Figure 35 show the local bus signals.



Figure 30. Local Bus Signals, Non-Special Signals Only (PLL Enabled)

Table 52 describes the general timing parameters of the local bus interface at $BV_{DD} = 3.3 \text{ V DC}$ with PLL disabled.

Table 52. Local Bus General Timing Parameters—PLL Bypassed

At recommended operating conditions with BV_{DD} of 3.3 V ± 5%

Parameter	Symbol ¹	Min	Мах	Unit	Notes
Local bus cycle time	t _{LBK}	12		ns	2
Local bus duty cycle	t _{LBKH} /t _{LBK}	43	57	%	—
Internal launch/capture clock to LCLK delay	t _{LBKHKT}	2.3	4.0	ns	
Input setup to local bus clock (except LGTA/LUPWAIT)	t _{LBIVKH1}	5.8	—	ns	4, 5
LGTA/LUPWAIT input setup to local bus clock	t _{LBIVKL2}	5.7	—	ns	4, 5
Input hold from local bus clock (except LGTA/LUPWAIT)	t _{LBIXKH1}	-1.3	_	ns	4, 5



Table 52. Local Bus General Timing Parameters—PLL Bypassed (continued)

At recommended operating conditions with BV_{DD} of 3.3 V ± 5%

Parameter	Symbol ¹	Min	Мах	Unit	Notes
LGTA/LUPWAIT input hold from local bus clock	t _{LBIXKL2}	-1.3	_	ns	4, 5
LALE output negation to high impedance for LAD/LDP (LATCH hold time)	t _{LBOTOT}	1.5	_	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	t _{LBKLOV1}	_	-0.3	ns	
Local bus clock to data valid for LAD/LDP	t _{LBKLOV2}	—	-0.1	ns	4
Local bus clock to address valid for LAD	t _{LBKLOV3}	—	0.0	ns	4
Local bus clock to LALE assertion	t _{LBKLOV4}	—	0.0	ns	4
Output hold from local bus clock (except LAD/LDP and LALE)	t _{LBKLOX1}	-3.3	—	ns	4
Output hold from local bus clock for LAD/LDP	t _{LBKLOX2}	-3.3	_	ns	4
Local bus clock to output high Impedance (except LAD/LDP and LALE)	t _{LBKLOZ1}	—	0.2	ns	7
Local bus clock to output high impedance for LAD/LDP	t _{LBKLOZ2}	_	0.2	ns	7

Notes:

- The symbols used for timing specifications herein follow the pattern of t<sub>(First two letters of functional block)(signal)(state) (reference)(state) for inputs and t_{(First two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{LBIXKH1} symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
 </sub>
- 2. All timings are in reference to local bus clock for PLL bypass mode. Timings may be negative with respect to the local bus clock because the actual launch and capture of signals is done with the internal launch/capture clock, which precedes LCLK by t_{LBKHKT}.
- 3. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at BV_{DD}/2.
- 4. All signals are measured from BVDD/2 of the rising edge of local bus clock for PLL bypass mode to 0.4 x BVDD of the signal in question for 3.3-V signaling levels.
- 5. Input timings are measured at the pin.
- t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
- 7. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

NOTE

In PLL bypass mode, LCLK[n] is the inverted version of the internal clock with the delay of t_{LBKHKT} . In this mode, signals are launched at the rising edge of the internal clock and are captured at the falling edge of the internal clock with the exception of LGTA/LUPWAIT (which is captured on the rising edge of the internal clock).



At recommended operating conditions with OV_{DD} of 3.3 V ± 5%. All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 2).

Parameter	Symbol ¹	Min	Мах	Unit
Capacitive load for each bus line	Cb	—	400	pF

Notes:

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- 1. The symbols used for timing specifications herein follow the pattern t_{(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the t_{I2C} clock reference (K) going to the t_{I2C} clock reference (K) going to the t_{I2C} timing (I2) for the time that the data with respect to the t_{I2C} symbolizes I²C timing (I2) for the time that the data with respect to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the t_{I2C} clock reference (K) going to the t_{I2C} clock reference (K) going to the t_{I2C} timing (I2) for the time that the data with respect to the t_{I2C} clock reference (K) going to the t_{I2C} clock reference (K) going to the t_{I2C} timing (I2) for the time that the data with respect to the STOP condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time.}
- 2. As a transmitter, the MPC8572E provides a delay time of at least 300 ns for the SDA signal (referred to the VIHmin of the SCL signal) to bridge the undefined region of the falling edge of SCL to avoid unintended generation of START or STOP condition. When the MPC8572E acts as the I2C bus master while transmitting, the MPC8572E drives both SCL and SDA. As long as the load on SCL and SDA are balanced, the MPC8572E would not cause unintended generation of START or STOP condition. Therefore, the 300 ns SDA output delay time is not a concern. If, under some rare condition, the 300 ns SDA output delay time is required for the MPC8572E as transmitter, application note AN2919 referred to in note 4 below is recommended.
- 3. The maximum t_{I2OVKL} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
- 4. The requirements for I²C frequency calculation must be followed. Refer to Freescale application note AN2919, *Determining the I²C Frequency Divider Ratio for SCL*.

Figure 40 provides the AC test load for the I^2C .



Figure 40. I²C AC Test Load

Figure 41 shows the AC timing diagram for the I^2C bus.



Figure 41. I²C Bus AC Timing Diagram



High-Speed Serial Interfaces (HSSI)



Figure 53. Single-Ended Measurement Points for Rise and Fall Time Matching

The other detailed AC requirements of the SerDes Reference Clocks is defined by each interface protocol based on application usage. Refer to the following sections for detailed information:

- Section 8.3.2, "AC Requirements for SGMII SD2_REF_CLK and SD2_REF_CLK"
- Section 16.2, "AC Requirements for PCI Express SerDes Reference Clocks"
- Section 17.2, "AC Requirements for Serial RapidIO SD1_REF_CLK and SD1_REF_CLK"

15.2.4.1 Spread Spectrum Clock

SD1_REF_CLK/SD1_REF_CLK are designed to work with a spread spectrum clock (+0 to -0.5% spreading at 30-33 KHz rate is allowed), assuming both ends have same reference clock. For better results, a source without significant unintended modulation should be used.

SD2_REF_CLK/SD2_REF_CLK are not to be used with, and should not be clocked by, a spread spectrum clock source.

15.3 SerDes Transmitter and Receiver Reference Circuits

Figure 54 shows the reference circuits for SerDes data lane's transmitter and receiver.



Figure 54. SerDes Transmitter and Receiver Reference Circuits

The DC and AC specification of SerDes data lanes are defined in each interface protocol section below (PCI Express, Serial Rapid IO or SGMII) in this document based on the application usage:

- Section 8.3, "SGMII Interface Electrical Characteristics"
- Section 16, "PCI Express"



Symbol	Parameter	Min	Nominal	Max	Units	Comments
V _{TX-DC-CM}	The TX DC Common Mode Voltage	0	_	3.6	V	The allowed DC Common Mode voltage under any conditions. See Note 6.
I _{TX-SHORT}	TX Short Circuit Current Limit		—	90	mA	The total current the Transmitter can provide when shorted to its ground
T _{TX-IDLE-MIN}	Minimum time spent in Electrical Idle	50			UI	Minimum time a Transmitter must be in Electrical Idle Utilized by the Receiver to start looking for an Electrical Idle Exit after successfully receiving an Electrical Idle ordered set
T _{TX-IDLE-SET-TO-IDLE}	Maximum time to transition to a valid Electrical idle after sending an Electrical Idle ordered set	_		20	UI	After sending an Electrical Idle ordered set, the Transmitter must meet all Electrical Idle Specifications within this time. This is considered a debounce time for the Transmitter to meet Electrical Idle after transitioning from L0.
T _{TX-IDLE-TO-DIFF} -DATA	Maximum time to transition to valid TX specifications after leaving an Electrical idle condition	_		20	UI	Maximum time to meet all TX specifications when transitioning from Electrical Idle to sending differential data. This is considered a debounce time for the TX to meet all TX specifications after leaving Electrical Idle
RL _{TX-DIFF}	Differential Return Loss	12	—	_	dB	Measured over 50 MHz to 1.25 GHz. See Note 4
RL _{TX-CM}	Common Mode Return Loss	6	—	_	dB	Measured over 50 MHz to 1.25 GHz. See Note 4
Z _{TX-DIFF-DC}	DC Differential TX Impedance	80	100	120	Ω	TX DC Differential mode Low Impedance
Z _{TX-DC}	Transmitter DC Impedance	40	_		Ω	Required TX D+ as well as D- DC Impedance during all states
L _{TX-SKEW}	Lane-to-Lane Output Skew	_	—	500 + 2 UI	ps	Static skew between any two Transmitter Lanes within a single Link
C _{TX}	AC Coupling Capacitor	75	_	200	nF	All Transmitters shall be AC coupled. The AC coupling is required either within the media or within the transmitting component itself. See Note 8.



Characteristic	Symbol	Ra	nge	Unit	Notos
Characteristic	Symbol	Min	Мах	Unit	NOLES
Differential Input Voltage	V _{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J _D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J _{DR}	0.55	_	UI p-p	Measured at receiver
Total Jitter Tolerance ¹	J _T	0.65	_	UI p-p	Measured at receiver
Multiple Input Skew	S _{MI}	_	24	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	_	10 ⁻¹²	_	_
Unit Interval	UI	800	800	ps	+/– 100 ppm

Table 72. Receiver AC Timing Specifications—1.25 GBaud

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 59. The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

Characteristic	Symbol	Ra	nge	Unit	Natas	
Characteristic	Gymbol	Min	Мах	Unit	NOLES	
Differential Input Voltage	V _{IN}	200	1600	mV p-p	Measured at receiver	
Deterministic Jitter Tolerance	J _D	0.37	—	UI p-p	Measured at receiver	
Combined Deterministic and Random Jitter Tolerance	J _{DR}	0.55	—	UI p-p	Measured at receiver	
Total Jitter Tolerance ¹	J _T	0.65	_	UI p-p	Measured at receiver	
Multiple Input Skew	S _{MI}	_	24	ns	Skew at the receiver input between lanes of a multilane link	
Bit Error Rate	BER	—	10 ⁻¹²	—	—	
Unit Interval	UI	400	400	ps	+/– 100 ppm	

Table 73. Receiver AC Timing Specifications—2.5 GBaud

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 59. The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.



Package Description

- 5. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
- 6. Parallelism measurement shall exclude any effect of mark on top surface of package.

18.3 Pinout Listings

Table 76 provides the pin-out listing for the MPC8572E 1023 FC-PBGA package.

Table 76. MPC8572E Pinout Listing

Signal	Signal Name	ne Package Pin Number		Power Supply	Notes					
DDR SDRAM Memory Interface 1										
D1_MDQ[0:63]	Data	D15, A14, B12, D12, A15, B15, B13, C13, C11, D11, D9, A8, A12, A11, A9, B9, F11, G12, K11, K12, E10, E9, J11, J10, G8, H10, L10, M11, F10, G9, K9, K8, AC6, AC7, AG8, AH9, AB6, AB8, AE9, AF9, AL8, AM8, AM10, AK11, AH8, AK8, AJ10, AK10, AL12, AJ12, AL14, AK14, AL11, AM11, AK13, AM14, AM15, AJ16, AL18, AM18, AJ15, AL15, AK17, AM17	I/O	GV _{DD}	_					
D1_MECC[0:7]	Error Correcting Code	M10, M7, R8, T11, L12, L11, P9, R10	I/O	GV _{DD}	—					
D1_MAPAR_ERR	Address Parity Error	P6	I	GV _{DD}	_					
D1_MAPAR_OUT	Address Parity Out	W6	0	GV _{DD}	_					
D1_MDM[0:8]	Data Mask	C14, A10, G11, H9, AD7, AJ9, AM12, AK16, N11	0	GV _{DD}	_					
D1_MDQS[0:8]	Data Strobe	A13, C10, H12, J7, AE8, AM9, AM13, AL17, N9	I/O	GV _{DD}	_					
D1_MDQS[0:8]	Data Strobe	D14, B10, H13, J8, AD8, AL9, AJ13, AM16, P10	I/O	GV _{DD}	_					
D1_MA[0:15]	Address	Y7, W8, U6, W9, U7, V8, Y11, V10, T6, V11, AA10, U9, U10, AD11, T8, P7	0	GV _{DD}						
D1_MBA[0:2]	Bank Select	AA7, AA8, R7	0	GV_DD						
D1_MWE	Write Enable	AC12	0	GV _{DD}	—					



Package Description

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes			
Power and Ground Signals								
GND	Ground	A18, A25, A29, C3, C6, C9, C12, C15, C20, C22, E5, E8, E11, E14, F3, G7, G10, G13, G16, H5, H21, J3, J9, J12, J18, K7, L5, L13, L15, L16, L21, M3, M9, M12, M14, M16, M18, N7, N13, N15, N17, N19, N21, N23, P5, P12, P14, P16, P20, P22, R3, R9, R11, R13, R15, R17, R19, R21, R23, R26, T7, T12, T14, T16, T18, T20, T22, T30, U5, U11, U13, U15, U16, U17, U19, U21, U23, U25, V3, V9, V12, V14, V16, V18, V20, V22, W7, W11, W13, W15, W17, W19, W21, W27, W32, Y5, Y12, Y14, Y16, Y18, Y20, AA3, AA9, AA13, AA15, AA17, AA19, AA21, AA30, AB7, AB26, AC5, AC11, AC13, AD3, AD9, AD14, AD17, AD22, AE7, AE13, AF5, AF11, AG3, AG9, AG15, AG19, AH7, AH13, AH22, AJ5, AJ11, AJ17, AK3, AK9, AK15, AK24, AL7, AL13, AL19, AL26						
XGND_SRDS1	SerDes Transceiver Pad GND (xpadvss)	C23, C27, D23, D25, E23, E26, F23, F24, G23, G27, H23, H25, J23, J26, K23, K24, L27, M25	_					
XGND_SRDS2	SerDes Transceiver Pad GND (xpadvss)	AD23, AD25, AE23, AE27, AF23, AF24, AG23, AG26, AH23, AH25, AJ27	_	_				

Table 76. MPC8572E Pinout Listing (continued)



Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes	
25 When exerting in DDD2 mode, express Dr. MDICI01 to ground through 40.2.0.4 (full strength mode) or 20.4.0 (holf strength						

25. When operating in DDR2 mode, connect Dn_MDIC[0] to ground through 18.2-Ω (full-strength mode) or 36.4-Ω (half-strength mode) precision 1% resistor, and connect Dn_MDIC[1] to GVDD through 18.2-Ω (full-strength mode) or 36.4-Ω (half-strength mode) precision 1% resistor. When operating in DDR3 mode, connect Dn_MDIC[0] to ground through 20-Ω (full-strength mode) or 40-Ω (half-strength mode) precision 1% resistor, and connect Dn_% resistor, and connect Dn_MDIC[1] to GVDD through 20-Ω (full-strength mode) or 40-Ω (half-strength mode) precision 1% resistor. These pins are used for automatic calibration of the DDR IOs.

- 26. These pins should be connected to XVDD_SRDS1.
- 27. These pins should be pulled to ground (XGND_SRDS1) through a 300- Ω (±10%) resistor.
- 28. These pins should be left floating.
- 29. These pins should be pulled up to TVDD through a 2–10 K Ω resistor.
- 30. These pins have other manufacturing or debug test functions. It is recommended to add both pull-up resistor pads to OVDD and pull-down resistor pads to GND on board to support future debug testing when needed.
- 31. DDRCLK input is only required when the MPC8572E DDR controller is running in asynchronous mode. When the DDR controller is configured to run in synchronous mode via POR setting cfg_ddr_pll[0:2]=111, the DDRCLK input is not required. It is recommended to tie it off to GND when DDR controller is running in synchronous mode. See the MPC8572E PowerQUICC[™] III Integrated Host Processor Family Reference Manual Rev.0, Table 4-3 in section 4.2.2 "Clock Signals", section 4.4.3.2 "DDR PLL Ratio" and Table 4-10 "DDR Complex Clock PLL Ratio" for more detailed description regarding DDR controller operation in asynchronous and synchronous modes.
- 32. EC_GTX_CLK125 is a 125-MHz input clock shared among all eTSEC ports in the following modes: GMII, TBI, RGMII and RTBI. If none of the eTSEC ports is operating in these modes, the EC_GTX_CLK125 input can be tied off to GND.
- 33. These pins should be pulled to ground (GND).
- 34. These pins are sampled at POR for General Purpose configuration use by software. Their value has no impact on the functionality of the hardware.



System Design Information

21.6 Pull-Up and Pull-Down Resistor Requirements

The MPC8572E requires weak pull-up resistors (2–10 k Ω is recommended) on open drain type pins including I²C pins and MPIC interrupt pins.

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in Figure 66. Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion gives unpredictable results.

The following pins must NOT be pulled down during power-on reset: DMA_DACK[0:1], EC5_MDC, HRESET_REQ, TRIG_OUT/READY_P0/QUIESCE, MSRCID[2:4], MDVAL, and ASLEEP. The TEST_SEL pin must be set to a proper state during POR configuration. For more details, refer to the pinlist table of the individual device.

21.7 Output Buffer DC Impedance

The MPC8572E drivers are characterized over process, voltage, and temperature. For all buses, the driver is a push-pull single-ended driver type (open drain for I^2C).

To measure Z_0 for the single-ended drivers, an external resistor is connected from the chip pad to OV_{DD} or GND. Then, the value of each resistor is varied until the pad voltage is $OV_{DD}/2$ (see Figure 64). The output impedance is the average of two components, the resistances of the pull-up and pull-down devices. When data is held high, SW1 is closed (SW2 is open) and R_P is trimmed until the voltage at the pad equals $OV_{DD}/2$. R_P then becomes the resistance of the pull-up devices. R_P and R_N are designed to be close to each other in value. Then, $Z_0 = (R_P + R_N)/2$.



Figure 64. Driver Impedance Measurement



Table 85 summarizes the signal impedance targets. The driver impedances are targeted at minimum V_{DD} , nominal OV_{DD} , 105°C.

Impedance	Local Bus, Ethernet, DUART, Control, Configuration, Power Management	DDR DRAM	Symbol	Unit
R _N	45 Target	18 Target (full strength mode) 36 Target (half strength mode)	Z ₀	Ω
R _P	45 Target	18 Target (full strength mode) 36 Target (half strength mode)	Z ₀	Ω

Table 85. Impedance Characteristics

Note: Nominal supply voltages. See Table 1, $T_i = 105^{\circ}C$.

21.8 Configuration Pin Muxing

The MPC8572E provides the user with power-on configuration options which can be set through the use of external pull-up or pull-down resistors of 4.7 k Ω on certain output pins (see customer visible configuration pins). These pins are generally used as output only pins in normal operation.

While $\overline{\text{HRESET}}$ is asserted however, these pins are treated as inputs. The value presented on these pins while $\overline{\text{HRESET}}$ is asserted, is latched when $\overline{\text{HRESET}}$ deasserts, at which time the input receiver is disabled and the I/O circuit takes on its normal function. Most of these sampled configuration pins are equipped with an on-chip gated resistor of approximately 20 kΩ. This value should permit the 4.7-kΩ resistor to pull the configuration pin to a valid logic low level. The pull-up resistor is enabled only during $\overline{\text{HRESET}}$ (and for platform /system clocks after $\overline{\text{HRESET}}$ deassertion to ensure capture of the reset value). When the input receiver is disabled the pull-up is also, thus allowing functional operation of the pin as an output with minimal signal quality or delay disruption. The default value for all configuration bits treated this way has been encoded such that a high voltage level puts the device into the default state and external resistors are needed only when non-default settings are required by the user.

Careful board layout with stubless connections to these pull-down resistors coupled with the large value of the pull-down resistor should minimize the disruption of signal quality or speed for output pins thus configured.

The platform PLL ratio, DDR complex PLL and e500 PLL ratio configuration pins are not equipped with these default pull-up devices.

21.9 JTAG Configuration Signals

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in Figure 66. Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion gives unpredictable results.

Boundary-scan testing is enabled through the JTAG interface signals. The $\overline{\text{TRST}}$ signal is optional in the IEEE Std 1149.1 specification, but it is provided on all processors built on Power Architecture technology. The device requires $\overline{\text{TRST}}$ to be asserted during power-on reset flow to ensure that the JTAG boundary



System Design Information



Notes:

- 1. The COP port and target board should be able to independently assert HRESET and TRST to the processor to fully control the processor as shown here.
- 2. Populate this with a 10 Ω resistor for short-circuit/current-limiting protection.
- 3. The KEY location (pin 14) is not physically present on the COP header.
- 4. Although pin 12 is defined as a No-Connect, some debug tools may use pin 12 as an additional GND pin for improved signal integrity.
- 5. This switch is included as a precaution for BSDL testing. The switch should be closed to position A during BSDL testing to avoid accidentally asserting the TRST line. If BSDL testing is not being performed, this switch should be closed to position B.
- 6. Asserting SRESET causes a machine check interrupt to the e500 cores.